XERZ 2 01604

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

| RESPONSE TO INTERVIEW SUMMARY | Title: METHOD FOR HIGH-THROUGHPUT SCREENING ASSAY SAMPLE PREPARATION AND ANALYSIS | |
|--|--|-------------------------|
| | First Named Inventor: | Richard H. Bruce et al. |
| | Application No.: | 10/719,961 |
| | Filing Date: | November 21, 2003 |
| | Confirmation No. | 3572 |
| | Examiner: | Brian J. Sines |
| Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450 | Art Unit: | 1797 |
| | Notice of Allowance: | June 17, 2008 |

Dear Sir:

As stated in the Interview Summary (of April 21, 2008), on April 15, 2008 Applicants discussed the final rejection of January 15, 2008. An agreement was reached whereby the Examiner indicated a Notice of Allowance would be issued. The Notice was subsequently issued on June 17, 2008.

Respectfully submitted,

| 7-22-09 | Fay Sharpe LLP |
|---------|--|
| Date | Mark S./Svát, Reg. No. 34,261 1100 Superior Avenue, Seventh Floor |
| | Cleveland, OH 44114-2579 |
| | 216-861-5582 |

| CERTIFICATE OF TRANSMISSION | | | |
|--|-----------------------|--|--|
| I hereby certify that this correspondence (and any item referred to herein as being attached or enclosed) is (are) being transmitted to the USPTO by electronic transmission via the EFS Web on the date indicated below.) | | | |
| 7-22-08 | - Davin Long Ht- | | |
| Date | Marillan M. E. C. II. | | |